

	Monday	Tuesday	Wednesday	Thursday	Friday
08:30		SMM / Conductive AFM	Uncertainty evaluation / Monte Carlo	Finite element method (FEM)	Optical techniques for thermal characterisation
08:40		F. Piquemal (LNE)			
08:50					
09:00		Break time	S. Demeyer (LNE)	P. Klapetek (CMI)	S. Dilhaire (LOMA)
09:10					
09:20					
09:30		PFM / KPFM	Coffee break around posters	Coffee break around posters	Coffee break around posters
09:40					
09:50					
10:00		B. Gautier (INL)	Mathematical & computational methods (Artificial intelligence)	Molecular dynamics (MD)	Spectroscopy for optical characterisation (Raman)
10:10					
10:20		Coffee break around posters			
10:30					
10:40			L. Coquelin (LNE)	M. Isaiev (LEMTA)	G. Nataf (GREMAN)
10:50					
11:00					
11:10		Magnetic characterisation		Free time	Round table: Challenges and perspectives
11:20					
11:30					
11:40		S. Sievers (PTB)			
11:50					
12:00					
12:10					
12:20					
12:30	Welcome			Lunch	Lunch
12:40					
12:50					
13:00		Lunch			
13:10					
13:20					
13:30	Lunch			Free time	
13:40					
13:50					
14:00					
14:10		Free time			
14:20					
14:30	Getting start with metrology			Density functional theory (DFT)	
14:40					
14:50	F. Piquemal (LNE) / N. Fleurence (LNE)	SPM thermal characterisation		C. Adessi (ILM)	Color code:
15:00	Break time				Modelling / calculation courses
15:10	Dimensional characterisation (AFM/SFM)	S. Gomès (CETHIL)			Technical courses
15:20				Break time	Informal exchanges
15:30					Practical courses
15:40	A. Delvallée (LNE)				
15:50					
16:00		Break time	Free time	Ellipsometry for optical characterisation	
16:10					
16:20	Coffee break around posters	Practical sessions: -Piezo AFM calibration -Image analysis / processing -Monte carlo application -Scan type SPM mode -C-AFM / SMM calibration		Andreas Hertwig (BAM)	
16:30					
16:40					
16:50	SCM/SSRM				
17:00					
17:10					
17:20		Coffee break around posters			
17:30					
17:40					
17:50	R. Coq Germanicus (CRISMAT)				
18:00					
18:10	Break time	Practical sessions: -Piezo AFM calibration -Image analysis / processing -Monte carlo application -Scan type SPM mode -C-AFM / SMM calibration			
18:20					
18:30	3w				
18:40					
18:50					
19:00		Break time			
19:10					
19:20		Analytical and hybride techniques		Practical sessions: -Piezo AFM calibration -Image analysis / processing -Monte carlo application -Scan type SPM mode -C-AFM / SMM calibration	
19:30	O. Bourgeois (NEEL)				
19:40					
19:50					
20:00	Welcome cocktail	S. Gomès (CETHIL) / F. Piquemal (LNE)			
20:10					
20:20					
20:30					
20:40					
20:50	Dinner	Dinner	Dinner	Dinner	
21:00					
21:10					
21:20					
21:30					
21:40			Networks/projects for measurements at the nanoscale: GdR (NAME, CarmaNano), C'Nano, NanoMesureFrance, European joint research project (JRP ELENA)		
21:50		Demonstration of correlative and hybride measurements			
22:00	Sponsors exhibitions				
22:10					
22:20					
22:30					